

**Search Notes**

Application/Control No.

10/730,006

Examiner

Eric Hug

Applicant(s)/Patent under  
Reexamination

KAMIJO ET AL.

Art Unit

1731

**SEARCHED**

Class	Subclass	Date	Examiner
162	25 27 28 18	12/10/2007	EH
162	52 56 60		
162	70 71		
162	76 78		
162	90 91		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner
162	all above	12/10/2007	EH

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
EAST- USPAT, USOCR, PGPUB, EPO, JPO, Derwent	12/10/2007	EH
Assignee and inventors search		
D21B 1/16, 9/10 D21C 9/02, 3/22, 1/06		
Interferences (below):		
((chips with bleach\$ with (refin\$ or beat\$) with (alkal\$ or caustic)).clm.		
((chips with bleach\$ with (refin\$ or beat\$) with wash\$).clm.		